



Association for Coordinate Metrology Canada
Association canadienne de métrologie de coordonnées

2006 ACMC Annual Workshop
NRC-Institute for National Measurement Standards
Ottawa, Ontario
22-23 June 2006

AGENDA

Thursday, 22 June 2006

- 08:30 - 08:50 **CONFERENCE REGISTRATION**
Coffee & breakfast refreshments
- 08:50 - 09:00 **Welcoming Remarks**
Dan Connelly, ACMC Chairman
James McLaren, Director General, NRC-Institute for National Measurement Standards
- 09:00 - 09:45 **User issues in CMM touch probes**
Adam Wozniak
Institute of Metrology and Measuring Systems, Warsaw University of Technology
- 09:45 - 10:30 **Machine Dynamics and Performance when Scanning**
Paul Gane
Technical Sales Manager for CMM Products, Renishaw (Canada) Limited
- 10:30 - 10:45 **COFFEE BREAK**
- 10:45 - 11:45 **Open forum discussion on CMM probing and probe calibration**
Panel Chair: Dan Connelly
Panel Members: Kostadin Doytchinov, Paul Gane, Greg Hetland, René Mayer, Adam Wozniak
- 11:45 - 12:45 **An Introduction to the White-Light Scanning Technology**
Steve Albrecht
District Sales Manager, Capture 3D, Inc.
- 12:45 - 13:45 **LUNCH**
- 13:45 - 14:30 **Metrology Interoperability—What is it, how do we achieve it, and what are its impediments?**
John Horst
Metrology Interoperability Project Manager, NIST
- 14:30 - 15:30 **Roundtrip Integration of CAD with CMMs—Practical Applications of an Integrated Planning, Measuring, Analyzing and Reporting Process**
Carlo R. Algera
Regional Manager, Origin International Inc.
- 15:30 - 15:45 **COFFEE BREAK**

15:45 - 17:00 **Recommended Practice for CMM Calibration: A project of the new NCSL International Dimensional Metrology Committee**
Jim Salisbury
Chair, Dimensional Metrology Committee, NCSL International
Corporate Metrologist, Mitutoyo America Corporation

An open discussion will follow.

17:00 - 17:30 **ACMC Business**
Annual Report and Election of Officers

17:30 - 18:15 **Open Discussions and Vendor's Time**

18:30 - 19:00 **RECEPTION** (Cash Bar)
Lower Rooftop Terrace, Ottawa Congress Centre

19:00 **DINNER**
Café Nicole, Novotel

Friday, 23 June 2006

08:00 - 08:30 **CONFERENCE REGISTRATION**
Coffee & breakfast refreshments

08:30 - 10:30 **Tolerances that you can't inspect. GD&T interpretation by people and software**
Ed Morse, Professor
Center for Precision Metrology, The University of North Carolina at Charlotte

10:30 - 10:45 **COFFEE BREAK**

10:45 - 11:45 **GD&T—Implications of Profile Tolerancing**
Greg Hetland, President
International Institute of GD&T, USA

11:45 - 12:30 **Open forum on GD&T: discussions of real drawings and solutions—bring your problem!**
Panel Chair: Dr. Greg Hetland
Panel Members: Carlo Algera, Kostadin Doytchinov, Ed Morse, Jim Salisbury

12:30 - 13:30 **LUNCH**

13:30 - 15:00 **Laboratory Tours**
Optional visits to the metrology labs of the NRC: Dimensional Metrology (CMM), Time and Frequency (Atomic clock), Institute for Information Technologies—3D scanning technologies